

IN THE SPECIFICATION:

Page 1, lines 1 to 10, replace the topic headings and paragraphs with the following amended topic headings and paragraphs.

~~DESCRIPTION~~

~~High-speed measuring device and method based on a confocal microscopy principle~~

~~TECHNICAL FIELD~~

BACKGROUND OF THE INVENTION

FIELD OF THE INVENTION

The invention relates to a scanning system and a method based on the principle of confocal microscopy ~~in accordance with the generic clause of claim 1.~~

THE PRIOR ART

Such scanning systems are used for scanning an object and ~~to permit for~~ enabling both scanning of a point along an axis (two-dimensional scanning)[7] and scanning of a surface disposed about an axis (three-dimensional scanning). Thus, such a device is suitable for a point sensor and a flat panel sensor.

~~DESCRIPTION OF THE RELATED ART~~

Page 7, lines 17 to 19, replace the figure description with the following amended description.

Figs. 12A ~~to~~and 12B show an arrangement of glass wedges<sup>[7]</sup> which can be used according to an improved development of the invention<sup>[7]</sup> for changing the optical thickness of the beam path, in two positions, and